

<b>Search Notes</b> 				<b>Application/Control No.</b> 10/790,220 <b>Examiner</b> Richard H. Kim	<b>Applicant(s)/Patent under Reexamination</b> OKAZAKI ET AL. <b>Art Unit</b> 2871	
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>		
Class	Subclass	Date	Examiner		DATE	EXMR
				No additional search required	2/24/2006	RHK
<b>INTERFERENCE SEARCHED</b>						
Class	Subclass	Date	Examiner			